EE 735 Assignment 4

Drain Current Models of MOSFETs

Non Extendible Deadline: 5 March 2025 11:59 pm(100% Penalty for Late Submission)

Implement all codes using Python

Hints, assumptions, and instructions:

- 1. Please define all input variables at the beginning of your code and use proper comments while developing the code. Your code must work for other input values too.
- 2. It is mandatory to submit your code along with the report (in pdf) in a single zip file. Name the file EE735_A4_RollNo_Name for this assignment.
- 3. Reference for the assignment:
 - Taur, Y., & Ning, T. H. (2009). Fundamentals of modern VLSI Devices. Chapter 2, Sections 3.1.1
 - Pao, H., & Sah, C. (1966). Effects of diffusion current on characteristics of metal-oxide (insulator)-semiconductor transistors. Solid-State Electronics, 9(10), 927–937. https://doi.org/10.1016/0038-1101(66)90068-2

Problems

Question1

Consider a NMOS transistor with a p doped Si substrate with doping $N_A = 1 \times 10^{17} cm^{-3}$ and thickness $t = 1\mu m$, SiO_2 as the dielectric material with oxide thickness $t_{ox} = 20nm$, and n+ doped poly-silicon gate (Consider the poly-silicon to be heavily doped such that $E_{f_m} = E_{c_m}$) and thickness $t_m = 10nm$. Dimensions of MOSFET $L = W = 1\mu m$. Vary the values of V_D and V_G from 0 to 5V. Assume $\mu_n = 200cm^2/Vs$.

- A. Estimate the value of the surface potential ψ_s at source and drain ends of the MOSFET for $V_G = V_D = 5V$.
- B. Numerically solve the Pao-Sah models for the given MOSFET. Plot transfer $(I_D V_G)$ characteristics for different V_D values $(V_D = 0.2 \text{V} \text{ and } 2 \text{V})$ and output $(I_D V_D)$ characteristics for different V_G values $(V_G = 1.5 \text{V} \text{ and } 3 \text{V})$.

C. Compare your results with the Piecewise Linear model of a MOSFET.

For the Pao-Sah model, the drain current can be determined using the equations:

$$I_D = \mu_{eff} \frac{W}{L} \int_0^{V_{DS}} \left[-Q_I(V) \right] dV$$

For an n type MOSFET,

$$[-Q_{I}(V)] = q \int_{\delta}^{\psi_{s}} \frac{\frac{n_{i}^{2}}{N_{A}} \exp \frac{q(\psi-V)}{kT}}{-\frac{d\psi}{dx}} d\psi$$
where, $-\frac{d\psi}{dx} = \sqrt{\frac{2kTN_{A}}{\epsilon_{Si}}} \left[\frac{q\psi}{kT} + \frac{n_{i}^{2}}{N_{A}^{2}} \exp \frac{q(\psi-V)}{kT}\right]^{0.5}$
 ψ_{s} is calculated using the equation:
$$V_{GS} = V_{FB} + \psi_{s} + \frac{\sqrt{2kTN_{A}\epsilon_{Si}}}{C_{ox}} \left[\frac{q\psi_{s}}{kT} + \frac{n_{i}^{2}}{N_{A}^{2}} \exp \frac{q(\psi_{s}-V)}{kT}\right]^{0.5}$$

The current equation using the Piecewise Linear Model of a MOSFET are given by:

$$I_D = \begin{cases} 0, & \text{if } V_{GS} > V_{th} \\ \mu_{eff} C_{ox} \frac{W}{L} V_{DS} \left(V_{GS} - V_{th} - 0.5 V_{DS} \right), & \text{if } V_{DS} > V_{GS} - V_{th} \\ \mu_{eff} C_{ox} \frac{W}{L} \frac{\left(V_{GS} - V_{th} \right)^2}{2}, & \text{if } V_{DS} < V_{GS} - V_{th} \end{cases}$$